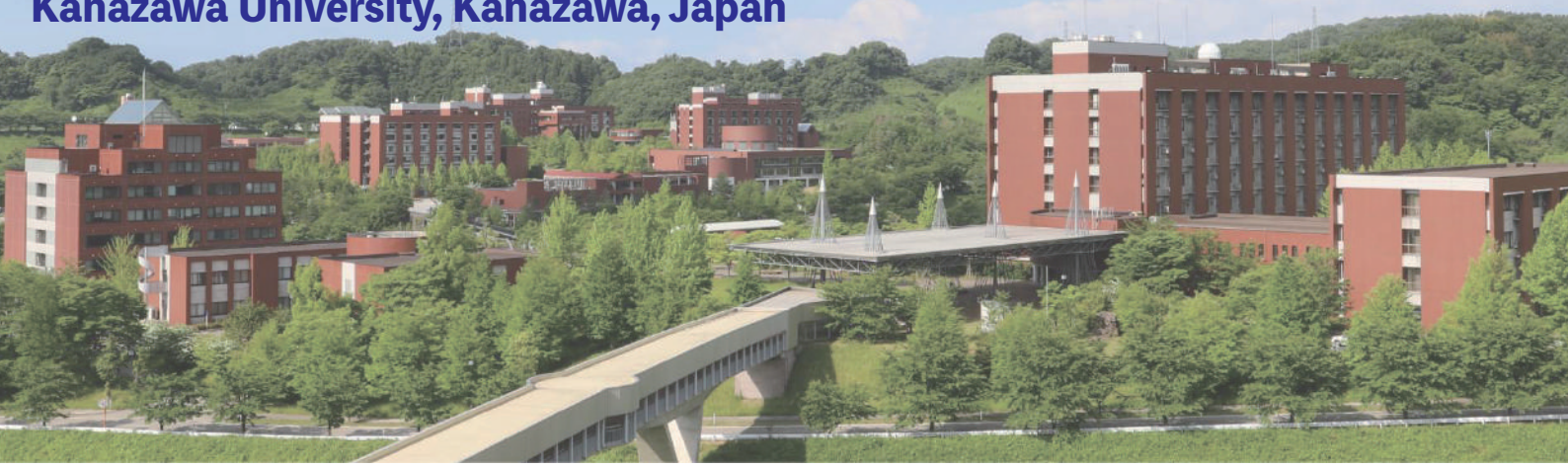
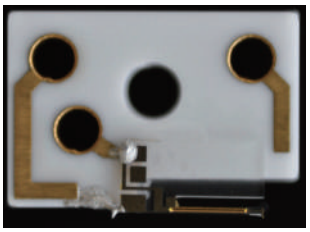
The International Workshop on AFM/STM Using qPlus Sensors and Related Techniques (qPlus Workshop 2026)

October 29–30, 2026
Kanazawa University, Kanazawa, Japan



qPlus sensors have successfully opened the field of nano- and atomic-scale surface observation and characterization based on scanning probe microscopy techniques and have delivered significant scientific and technological advances.
This workshop will bring together researchers working on AFM/STM using qPlus sensors and related techniques to discuss recent advances, experimental techniques, instrumentation, and future developments.



qPlus sensor



Prof. Franz J. Giessibl at Kanazawa University

Co-Chairs
Toyoko Arai (Kanazawa University)
Franz J. Giessibl (University of Regensburg / Kanazawa University)

Invited Speakers (Tentative)
Franz J. Giessibl (University of Regensburg / Kanazawa University)
Jascha Repp (University of Regensburg)
Takashi Ichii (Kyoto University)
Shigeki Kawai (National Institute for Materials Science)
Toshu An (Japan Advanced Institute of Science and Technology)
Masayuki Abe (The University of Osaka)
Yuji Miyato (Ryukoku University)
Hiroyuki Mogi (University of Tsukuba)
Yuuki Yasui (The University of Tokyo)
Norio Okabayashi (Kanazawa University)
Hiroaki Ooe (Yokohama City University)

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Co-Organizer:
Kanazawa University J-PEAKS

Supporting Organization:
Next Generation Nanoprobe Technology Committee
Thin Film and Surface Physics Division of JSAP

Further details will be announced on the workshop website.